

# Shot Noise in the Presence of Spin-Flip Scattering

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Shot noise is a time-dependent current fluctuation due to the discrete character of the electron charge. Here we address shot noise in a spin-resolved tunneling system under the influence of spin-flip scattering within a master equation approach. We find that the average current  $\langle I \rangle$  and Fano factor  $\gamma$  (“normalized noise”) present contrasting behavior for differing spin-flip time ratios:  $\langle I \rangle$  decreases while  $\gamma$  increases for  $\tau_{\uparrow\downarrow} > \tau_{\downarrow\uparrow}$  as compared to the  $\tau_{\uparrow\downarrow} = \tau_{\downarrow\uparrow}$  case and vice versa for  $\tau_{\uparrow\downarrow} < \tau_{\downarrow\uparrow}$ .

Spin-dependent transport in tunneling structures is a fascinating subject. So far the bulk of experimental and theoretical investigations has been on metallic layered systems. This focus is now turning to more versatile semiconductor heterostructures. More specifically, spin-polarized transport – an obvious possibility in spin-dependent geometries [1] – has just recently been achieved in Mn-based II-VI and III-V doped semiconductor diodes [2, 3, 4]. These seminal experiments open up new venues for further advances in the emerging field of spintronics in semiconductors – where the spin of the carrier, rather than its charge, runs the show [5, 6].

So far spin injection [2, 3, 4] has been demonstrated only at low temperatures and in the *diffusive* limit [7]. Spin injection at room temperatures, relevant for real device applications, remains a challenge. However, investigations at low temperatures are fundamentally important for understanding general features/properties of spin-polarized transport which may turn out relevant at high temperatures. Conceivably, some detrimental spin-flip effects contaminating low temperature transport may very well survive at higher temperatures.

Here we investigate spin-flip effects on transport through a spin-resolved tunneling system [8], Fig. 1. More specifically, we are interested in spin-flip effects on shot noise. Shot noise is a dynamic current fluctuation arising from the *particular* (or granular) nature of the electron charge. Shot noise investigations have become a major subject of research in the last decade or so [9, 10]. Common wisdom has it that shot noise measurements supplement information contained in the average current. Here in particular we find that spin-flip processes affect the average current and shot noise

in a *contrasting* fashion; in a limited parameter range, while shot noise is suppressed the average current is enhanced and vice versa, Fig. 2.

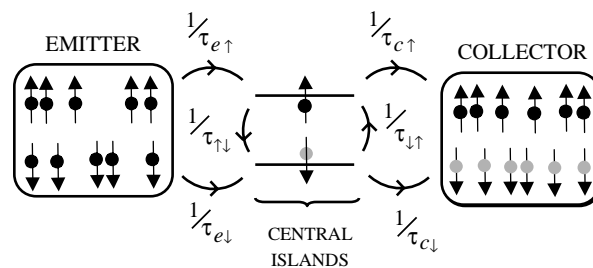


Figure 1. Schematic representation of a resonant-tunneling system with a semimagnetic quantum well/dot. Spin up electrons from the emitter can hop into the upper spin-up levels (“island up”) and subsequently either spin flip into the lower spin-down levels (“island down”) or hop out to the collector. Spin down electrons perform similar transitions. All these hops are described by “transition times”  $\tau$ 's; the corresponding transition rates are proportional to  $1/\tau$ 's as indicated. Note that hopping between the central islands involves spin flip processes characterized by  $\tau_{\uparrow\downarrow}$  and  $\tau_{\downarrow\uparrow}$ .

*Physical system.* We consider a II-VI double-barrier tunneling structure with a Manganese-based quantum well/dot. In the presence of an external magnetic field, the *s-d* exchange interaction between a traversing electron and the *d* electrons of the Mn gives rise to a spin-dependent quantum well/dot potential. This in turn lifts the spin-up/spin-down degeneracy of the resonant level. Each exchange-split resonant level accepts electrons with only a well-defined spin component. Fig. 1 schematically shows the system geometry. In Fig. 1, the many possible electron transitions connecting the

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emitter, spin-split levels (“islands” up and down) and collector are described by transition rates proportional to  $1/\tau$ , where  $\tau$  is, roughly speaking, the respective transition time. Observe that the hops between spin-resolved levels in Fig. 1 involve spin flip. Here we use distinct spin-flip times for the up-to-down and down-to-up transitions between the islands, i.e.,  $\tau_{\uparrow\downarrow} \neq \tau_{\downarrow\uparrow}$ ; this is certainly the case when the relevant spin-flip mechanism connecting the islands is the  $s$ - $d$  exchange interaction [11]. Our description, however, does not rely on any specific form of the spin-flip mechanism.

*Semiclassical description.* We model spin-resolved tunneling through a quantum well/dot in terms of classical hops among emitter, spin-split levels and collector as shown in Fig. 1 (see also inset in Fig. 2). Our approach is based on rate equations for the ensemble averaged number of electrons  $n_{\uparrow}(t)$  and  $n_{\downarrow}(t)$  in the islands up and down, respectively. These equations are directly derived from the system population master equation describing the probability  $p(n_{\uparrow}, n_{\downarrow}, t)$  of finding  $n_{\uparrow}$  and  $n_{\downarrow}$  electrons in the islands at time  $t$ . Island up (down) holds at most  $N_{\uparrow}$  ( $N_{\downarrow}$ ). Our transition rates take into account that no electrons can hop into a full island (“Pauli principle”) or out of an empty one. This type of correlation does affect current fluctuations arising from the discreteness of the electron charge.

*Average current and its fluctuations.* From the rate equations mentioned above we can easily determine the average current through the system. In the steady state  $\langle I \rangle = e\langle n_{\uparrow} \rangle / \tau_{c\uparrow} + e\langle n_{\downarrow} \rangle / \tau_{c\downarrow}$  ( $e$ : electron charge) and the average occupations  $\langle n_{\uparrow,\downarrow} \rangle = n_{\uparrow,\downarrow}(t \rightarrow \infty)$  depend on the several hopping times  $\tau$ 's and  $N_{\uparrow,\downarrow}$ . The current fluctuation is defined in terms of the ensemble average current-current correlation function  $\langle \delta i(t+t') \delta i(t') \rangle$ . Experimentally, the relevant quantity is the spectral power of the shot noise measured (usually) at zero frequency, i.e.,  $S(0) = 2 \int \langle \delta i(t+t') \delta i(t') \rangle dt$ . By introducing appropriate “hop-hop” correlation functions, which describe how likely a particular hop follows a previous one, we can relate  $S(0)$  to the variance matrix of the system [12]. This  $2 \times 2$  matrix is directly obtained from the master equation of the system. The resulting expressions for the zero-frequency shot noise  $S(0)$  and the elements of the variance matrix ( $\langle \delta n_{\uparrow} \delta n_{\downarrow} \rangle = \langle \delta n_{\downarrow} \delta n_{\uparrow} \rangle$ ,  $\langle (\delta n_{\uparrow})^2 \rangle$ , and  $\langle (\delta n_{\downarrow})^2 \rangle$ ) are too lengthy to be shown here [13].

*Results and discussions.* Fig. 2 displays curves for both  $\langle I \rangle / e$  (symbols) and the Fano factor  $\gamma = S(0) / 2e\langle I \rangle$  (lines) for the resonant-tunneling system in Fig. 1, with differing spin-flip time ratios. The normalizing factor  $2e\langle I \rangle$ , usually called ‘classical or full’ shot noise (Schottky), denotes the shot noise power spectral density for a stream of *uncorrelated* electrons with average current  $\langle I \rangle$ . The Fano factor is a convenient means to assess how correlations affect shot noise. In Figure 2 both average current and Fano factor are strongly affected by spin-flip processes. This can be

more clearly observed for  $\tau_{c\downarrow} / \tau_{c\uparrow}$  in the range 1 to 10 (or, equivalently, 0 to 1 in the horizontal log axis of Fig. 1) in which the flow of electrons from ‘island-up’ to the collector is suppressed. In this case, to arrive at the collector an electron has to necessarily go through ‘island-down’ thus undergoing spin flip. In this particular range, shot noise (Fano factor) and average current exhibit contrasting behavior for differing  $\tau_{\uparrow\downarrow} / \tau_{\downarrow\uparrow}$  ratios;  $\langle I \rangle$  decreases while  $\gamma$  increases for  $\tau_{\uparrow\downarrow} > \tau_{\downarrow\uparrow}$  as compared to the  $\tau_{\uparrow\downarrow} = \tau_{\downarrow\uparrow}$  case and vice versa for  $\tau_{\uparrow\downarrow} < \tau_{\downarrow\uparrow}$ . This trend is reversed in the  $[-1, 0]$  range. Hence shot noise and the average current are distinctively sensitive to spin flip.

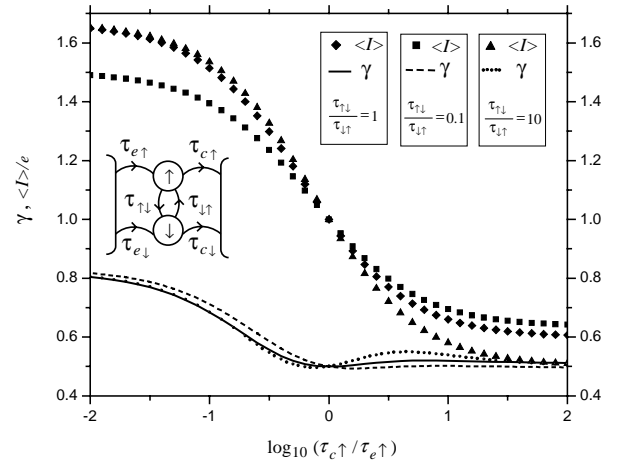


Figure 2. Average current and Fano factor for the resonant-tunneling system in Fig. 1 with differing spin-flip time ratios. We use  $N_{\uparrow} = N_{\downarrow} = 1$ ,  $\tau_{e\uparrow} = \tau_{e\downarrow} = \tau_{c\downarrow} = 1$ , in all curves (symbols for average currents and lines for Fano factors). We see that  $\langle I \rangle$  and  $\gamma$  depend on spin-flip scattering. All curves are particularly sensitive to the  $\tau_{\uparrow\downarrow} / \tau_{\downarrow\uparrow}$  ratio. In the  $[0, 1]$  range (horizontal axis), the average current and Fano factor exhibit contrasting behavior;  $\langle I \rangle$  decreases while  $\gamma$  increases for  $\tau_{\uparrow\downarrow} > \tau_{\downarrow\uparrow}$  as compared to the  $\tau_{\uparrow\downarrow} = \tau_{\downarrow\uparrow}$  case and vice versa for  $\tau_{\uparrow\downarrow} < \tau_{\downarrow\uparrow}$ .

Sumarizing, we have discussed spin-flip effects on spin-dependent transport in semimagnetic junctions with spin-split resonant levels. Our semiclassical description in terms of rate and master equations allows us to calculate both the average current and shot noise; the latter in terms of the variance matrix of the system. Interestingly enough, we find that the average current and shot noise are sensitive to spin flip (between the spin-split levels) in a contrasting way. In a limited parameter range, while the average current decreases (increases) the shot noise increases (decreases) as function of the ratio  $\tau_{\uparrow\downarrow} / \tau_{\downarrow\uparrow}$ .

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## References

- [1] J. C. Egues, Phys. Rev. Lett. **80**, 4578 (1998). For recent related works see Y. Guo *et al.*, J. Appl. Phys. **88**, 6614 (2000); Y. Guo *et al.*, Phys. Rev. B **63**, 214415 (2001); P. F. Farinas, Phys. Rev. B **64**, 161310(R) (2001); K. Chang and F. M. Peeters, Solid State Commun. **120**, 181 (2001); and Ref. [7] below.
- [2] R. Fiederling M. Kleim, G. Reuscher, W. Ossau, G. Schmidt, A Waag, and L. W. Molenkamp, Nature **402**, 787 (1999).
- [3] Y. Ohno D. K. Young, B. Beschoten, F. Matsukura, H. Ohno, and D. D. Awschalom, Nature **402**, 790 (1999).
- [4] B. T. Jonker Y. D. Park, B. R. Bennett, H. D. Cheong, G. Kioseglou, and A. Petrou, Phys. Rev. B **62**, 8180 (2000).
- [5] G. Prinz, Science **282**, 1660 (1998).
- [6] N. Samarth and D.D. Awschalom, *Quantum Devices and Circuits*, edited by Ismail, K.; Bandopadhyay, S.; Leburton, J.P.; (1997).
- [7] For a theoretical discussion of possible unique signatures for *coherent* spin filtering in connection with magnetoresistance, see J. C. Egues, C. Gould, G. Richter, and L. W. Molenkamp, Phys. Rev. B **64**, 195319 (2001)
- [8] F. G. Brito, J. F. Estanislau, and J. C. Egues J. Magn. Mater. 226-230, 457 (2001).
- [9] R. Landauer, Nature **392**, 658 (1998).
- [10] Ya. M. Blanter and M. Büttiker, Phys. Rep. **336**, 1 (2000).
- [11] J. C. Egues and J. W. Wilkins, Phys. Rev. B **58**, R16012 (1998).
- [12] J. C. Egues, S. Hershfield, and J. W. Wilkins, Phys. Rev. B **49**, 13517 (1994).
- [13] A detailed account of our calculation, along with expressions for the relevant quantities will be published elsewhere (F. G. Brito and J. C. Egues, in preparation).